

POLISHING COMPOSITION AND POLISHING METHOD

BACKGROUND OF THE INVENTION

Field of the Invention

5 [0001]

The present invention relates to a polishing composition and a polishing method.

Description of the Related Art

10 [0002]

In recent years, with multilayer-wiring on the surface of a semiconductor substrate, a so-called chemical mechanical polishing (CMP) art of polishing the semiconductor substrate for planarization has been used in manufacturing a device. The CMP is a method for planarizing the surface of a polishing object (object to be polished), such as a semiconductor substrate, using a polishing composition (slurry) containing abrasives, such as silica, alumina, and ceria, an anticorrosive, a surfactant, and the like. Examples of the polishing object (object to be polished) include silicon, polysilicon, a silicon oxide film (silicon oxide), silicon nitride, wiring lines containing a metal and the like, a plug, and the like.

25 For the polishing composition used in polishing a semiconductor substrate by the CMP, various proposals have been made so far.

[0003]

For example, PTL 1 describes a polishing composition for improving the polishing characteristics to polysilicon, particularly improving level difference elimination efficiency. The polishing composition
5 contains abrasives (colloidal silica) and an oxidant and has a pH of 6 or more. It is described that the polishing composition improves level difference elimination characteristics to a polishing object having a level difference because the oxidant applies a chemical
10 action to chemically polish the surface of polysilicon which is a polishing object in the composition having a pH of 6 or more.

Moreover, PTL 1 describes a polishing composition containing 500 ppm of polyvinylpyrrolidone having a
15 weight average molecular weight of 40,000 as an example of a water-soluble polymer which is an additive compounded in order to further improve the level difference elimination efficiency. The polishing composition has a pH of 9 and contains 0.1 mass% of
20 hydrogen peroxide.

[0004]

PTL 2 describes an additive for CMP abrasives containing an organic compound having an acetylene bond, a water-soluble vinyl polymer, and water, having a pH of
25 4 to 9, and capable of polishing an inorganic insulating film for semiconductors by being combined with a cerium oxide slurry for semiconductors. It is described that the compounding of the additive can improve the polishing

uniformity of the entire surface of the wafer plane to improve the planarization characteristics of the entire surface of the wafer plane. Polyvinylpyrrolidone is not illustrated as the water-soluble vinyl polymer.

5 [0005]

PTL 3 describes, as a polishing composition for the use of roughly polishing a silicon wafer, a polishing composition containing abrasives, a nitrogen containing water-soluble polymer (polyvinylpyrrolidone, content of
10 0.005 mass% or less) containing two kinds of the same structure different in weight average molecular weight (first nitrogen containing water-soluble polymer and second nitrogen containing water-soluble polymer), a basic compound, and water. Moreover, as the compounding
15 ratio of the two kinds of the nitrogen containing water-soluble polymers, First nitrogen containing water-soluble polymer (weight average molecular weight of 300,000 or more):Second nitrogen containing water-soluble polymer (weight average molecular weight of less than 300,000) =
20 5:1 to 1:20 is described.

Citation List

Patent Literature

[0006]

25 PTL 1: JP 2015-86355 A
PTL 2: JP 2008-85058 A
PTL 3: WO 2019/116833

SUMMARY OF THE INVENTION

[0007]

A step of manufacturing a semiconductor device includes polishing a polishing object having a polysilicon film (film containing a silicon material having a silicon-silicon bond) formed on a pattern containing a silicon nitride film (insulating film) by the CMP method to form circuit patterns containing the polysilicon film, for example. Examples of problems occurring in the polishing include the occurrence of dishing in which the upper surface of the circuit patterns containing the polysilicon films is dented in a dish shape, the occurrence of erosion by scraping off of the upper surface of the silicon nitride film between wiring lines, and the occurrence of a state in which the polysilicon film to be scraped off remains, so that the silicon nitride film between the circuit patterns is not exposed.

[0008]

Although the polishing composition described in PTL 1 aims at the suppression of the dishing, the polishing removal rate of the polysilicon film remarkably decreases because the oxidant is contained. The CMP abrasive described in PTL 2 contains cerium oxide as abrasives. The cerium oxide is generally expensive and easy to precipitate, and therefore is inferior in storage stability.

The polishing composition described in PTL 3 contains the water-soluble polymer having a molecular weight of 300,000 or more, and therefore is not suitable for "the use of polishing a polishing object having a film containing a silicon material having a silicon-silicon bond formed on a pattern containing an insulating film by the CMP method to form circuit patterns containing the silicon material having a silicon-silicon bond".

10 [0009]

It is an object of the present invention to provide a polishing composition suitable for the use of polishing a polishing object having a film containing a silicon material having a silicon-silicon bond formed on a pattern containing an insulating film by a CMP method to form circuit patterns containing the silicon material having a silicon-silicon bond (the above-described problems are suppressed) and also capable of suppressing a remarkable reduction in polishing removal rate.

20 [0010]

In order to solve the above-described problems, a polishing composition according to one aspect of the present invention contains abrasives, a first water-soluble polymer containing a polymer compound containing a lactam ring and having a weight average molecular weight of less than 300,000, a second water-soluble polymer containing a polymer compound containing a lactam ring and having a weight average molecular weight smaller

than that of the first water-soluble polymer, a basic compound, and water.

[0011]

The present invention can provide a polishing
5 composition suitable for the use of polishing a polishing
object having a film containing a silicon material having
a silicon-silicon bond formed on a pattern containing an
insulating film by a CMP method to form circuit patterns
containing the silicon material having a silicon-silicon
10 bond and also capable of suppressing a remarkable
reduction in polishing removal rate.

BRIEF DESCRIPTION OF THE DRAWINGS

[0012]

15 FIG. 1 is a cross-sectional view illustrating a
polishing object subjected to a polishing test in
Examples and an ideal polishing state of the polishing
object.

FIG. 2 is a plan view illustrating a state where a
20 polysilicon film does not remain on the polishing object
after subjected to the polishing test in Examples
(Excellent).

FIG. 3 is a plan view illustrating a state where the
polysilicon film partially remains on the polishing
25 object after subjected to the polishing test in Examples
but no problems occur (Good).

FIG. 4 is a plan view illustrating a state where
most of the polysilicon film remains on the polishing

object after subjected to the polishing test in Examples and a problem occurs (Poor).

DESCRIPTION OF THE PREFERRED EMBODIMENTS

5 [0013]

[One aspect of present invention]

As described above, a polishing composition according to one aspect of the present invention contains silica abrasives, a first water-soluble polymer
10 containing a polymer compound containing a lactam ring and having a weight average molecular weight of less than 300,000, a second water-soluble polymer containing a polymer compound containing a lactam ring and having a weight average molecular weight smaller than that of the
15 first water-soluble polymer, a basic compound, and water.

According to the polishing composition of one aspect of the present invention, due to the fact that both the first water-soluble polymer and the second water-soluble polymer are contained, the polishing characteristics in
20 polishing a polishing object containing a film containing a silicon material having a silicon-silicon bond is improved as compared with a polishing composition not containing both the first water-soluble polymer and the second water-soluble polymer or containing only either
25 one of them.

[0014]

Both the first water-soluble polymer and the second water-soluble polymer contain the polymer compound

containing a lactam ring and have a weight average molecular weight of less than 300,000. The weight average molecular weight of the second water-soluble polymer is smaller than the weight average molecular weight of the first water-soluble polymer. Due to the fact that both such first water-soluble polymer and second water-soluble polymer (weight average molecular weight of less than 300,000) are contained, in carrying out a polishing method including "polishing a polishing object having a film containing a silicon material having a silicon-silicon bond formed on a pattern containing an insulating film by a CMP method to form circuit patterns containing the silicon material having a silicon-silicon bond", dishing of the circuit patterns is suppressed, erosion of the insulating film is suppressed, and the occurrence of a state in which the insulating film between the circuit patterns is not exposed is suppressed as compared with the polishing composition not containing both of the first water-soluble polymer and the second water-soluble polymer or containing only either one of them.

[0015]

Even in the case where the two water-soluble polymers containing the polymer compound containing a lactam ring and different in weight average molecular weight are contained, when the weight average molecular weight of one of the water-soluble polymers is 300,000 or more, the state in which the insulating film between the

circuit patterns is not exposed tends to be reached in carrying out the above-described polishing method.

The polishing composition of one aspect of the present invention obtains the actions and the effects
5 described above due to containing both the first water-soluble polymer and the second water-soluble polymer and does not need to contain an oxidant, and therefore does not cause a remarkable reduction in polishing removal rate as in the polishing composition of PTL 1 containing
10 an oxidant.

[0016]

[Detailed description about one aspect of present invention]

Hereinafter, one aspect of the present invention is
15 described in detail.

<Polishing object>

Examples of the use of the polishing composition of one aspect of the present invention include polishing of a polishing object containing a film containing a silicon
20 material having a silicon-silicon bond.

Examples of the silicon material having a silicon-silicon bond include Si alloys, such as polysilicon (Poly-Si), amorphous silicon, single crystal silicon, n-type doped single crystal silicon, p-type doped single
25 crystal silicon, and SiGe, and the like, for example. In particular, the polishing composition is suitable for the use of polishing substances containing a polysilicon film.

The polishing object containing the film containing the silicon material having a silicon-silicon bond contains silicon oxide, silicon nitride, silicon carbonitride (SiCN), metal, and the like, for example, as materials other than the silicon material having a silicon-silicon bond.

[0017]

<Abrasives>

The polishing composition of one aspect of the present invention contains silica abrasives (abrasives containing silica particles). When cerium oxide is used as abrasives, a residue of the cerium oxide tends to remain on the polishing object after polishing. Therefore, it is not preferable to use the cerium oxide.

Examples of the kind of the silica particles include, but are not particularly limited thereto, fumed silica, colloidal silica, and the like and colloidal silica is preferable. Examples of a method for manufacturing colloidal silica include a sodium silicate process and a sol-gel process. Colloidal silica manufactured by either manufacturing method is suitably used as the silica particles configuring the polishing composition of one aspect of the present invention.

[0018]

However, colloidal silica manufactured by the sol-gel method is preferable from the viewpoint of reducing metal impurities. The colloidal silica manufactured by the sol-gel method is preferable because the content of

metal impurities or corrosive ions, such as chloride ions, having a property of diffusing in a semiconductor is low. The colloidal silica by the sol-gel method can be manufactured using conventionally known techniques.

5 Specifically, the colloidal silica can be obtained by performing a hydrolysis/condensation reaction using a hydrolyzable silicon compound (for example, alkoxysilane or a derivative thereof) as a raw material.

[0019]

10 The silica particles may have a cationic group. More specifically, the silica particles may be cation-modified silica particles or may be cation-modified colloidal silica. As the colloidal silica having a cationic group (cation-modified colloidal silica),
15 colloidal silica having an amino group immobilized on the surface is preferably mentioned. Examples of a method for manufacturing such colloidal silica having a cationic group include a method including immobilizing a silane coupling agent having amino groups, such as
20 aminoethyltrimethoxysilane, aminopropyltrimethoxysilane, aminoethyltriethoxysilane, aminopropyltriethoxysilane, aminopropyldimethylethoxysilane, aminopropylmethyldiethoxysilane, and aminobutyltriethoxysilane, on the surface of the silica
25 particles described in JP 2005-162533 A. Thus, the colloidal silica having an amino group immobilized on the surface (amino group-modified colloidal silica) can be obtained.

[0020]

The colloidal silica may have an anionic group. More specifically, the silica particles may be anion-modified silica particles or may be anion-modified
5 colloidal silica. Examples of the colloidal silica having an anionic group (anion-modified colloidal silica) preferably include colloidal silica having anionic groups, such as a carboxylic acid group, a sulfonic acid group, a phosphonic acid group, and an aluminic acid
10 group, immobilized on the surface. Examples of a method for manufacturing such colloidal silica having anionic groups include, but are not particularly limited thereto, a method including reacting a silane coupling agent having an anionic group at the terminal and colloidal
15 silica to each other, for example.

[0021]

As a specific example, when a sulfonic acid group is immobilized on the colloidal silica, the immobilization can be performed by a method described in "Sulfonic acid-
20 functionalized silica through of thiol groups" Chem. Commun. 246-247 (2003), for example. Specifically, colloidal silica having a sulfonic acid group immobilized on the surface (sulfonic acid-modified colloidal silica) can be obtained by coupling a silane coupling agent
25 having a thiol group, such as 3-mercaptopropyltrimethoxysilane, to colloidal silica, followed by oxidation of the thiol group with hydrogen peroxide.

[0022]

When a carboxylic acid group is immobilized on colloidal silica, the immobilization can be performed by a method described in "Novel Silane Coupling Agents
5 Containing a Photolabile 2-Nitrobenzyl Ester for Introduction of a Carboxy Group on the Surface of Silica Gel", Chemistry Letters, 3,228-229 (2000), for example. Specifically, colloidal silica having a carboxylic acid group immobilized on the surface (carboxylic acid-
10 modified colloidal silica) can be obtained by coupling a silane coupling agent containing photoreactive 2-nitrobenzyl ester to colloidal silica followed by irradiation with light.

[0023]

15 The shape of the silica particles is not particularly limited and may be a spherical shape or may be a non-spherical shape. Specific examples of the non-spherical shape include various shapes, such as polygonal column shapes, such as a triangular column and a square
20 column, a cylindrical shape, a bale shape in which a central portion of a column is more inflated than end portions, a doughnut shape in which a central portion of a disk is penetrated, a plate shape, a so-called cocoon shape having constriction in a central portion, a so-
25 called associative spherical shape in which a plurality of particles is integrated, a so-called konpeito-(pointed sugar candy ball-) like shape having a plurality

of projections on the surface, and a rugby ball shape but are not particularly limited thereto.

[0024]

The size of the silica particles is not particularly limited. However, the average primary particle diameter of the silica particles is preferably 20 nm or more, more preferably 40 nm or more, still more preferably 50 nm or more, and particularly preferably 60 nm or more. The average primary particle diameter of the silica particles is preferably 250 nm or less, more preferably 200 nm or less, still more preferably 150 nm or less, and particularly preferably 100 nm or less. Within such a range, defects, such as scratches, in the surface of the polishing object after polishing using the polishing composition can be suppressed. More specifically, the average primary particle diameter of the silica particles is preferably 20 nm or more and 250 nm or less, more preferably 40 nm or more and 200 nm or less, still more preferably 50 nm or more and 150 nm or less, and particularly preferably 60 nm or more and 100 nm or less. The average primary particle diameter of the silica particles is calculated based on the specific surface area of the silica particles measured by a BET method, for example.

[0025]

The average secondary particle diameter of the silica particles is preferably 50 nm or more, more preferably 80 nm or more, still more preferably 100 nm or

more, and particularly preferably 120 nm or more. The average secondary particle diameter of the silica particles is preferably 500 nm or less, more preferably 400 nm or less, still more preferably 300 nm or less, and particularly preferably 250 nm or less. Within such a range, defects, such as scratches, in the surface of the polishing object after polishing using the polishing composition can be suppressed. More specifically, the average secondary particle diameter of the silica particles is preferably 50 nm or more and 500 nm or less, more preferably 80 nm or more and 400 nm or less, still more preferably 100 nm or more and 300 nm or less, and particularly preferably 120 nm or more and 250 nm or less. The average secondary particle diameter of the silica particles can be measured by a dynamic light scattering method typified by a laser diffraction scattering method, for example.

[0026]

The average association degree of the silica particles is preferably 5.0 or less, more preferably 3.0 or less, and still more preferably 2.5 or less. The generation of the defects in the surface of the polishing object can be further reduced with a reduction in the average association degree of the silica particles. The average association degree of the silica particles is preferably 1.0 or more and more preferably 1.2 or more. With an increase in the average association degree of the silica particles, there is an advantage that the

polishing removal rate by the polishing composition is improved. The average association degree of the silica particles is obtained by dividing the value of the average secondary particle diameter of the silica particles by the value of the average primary particle diameter of the silica particles.

[0027]

The aspect ratio of the silica particles is not particularly limited and is preferably less than 2.0, more preferably 1.8 or less, and still more preferably 1.5 or less. Within such a range, defects in the surface of the polishing object can be further reduced. The aspect ratio is the average of values obtained by taking the smallest rectangle circumscribing an image of the silica particles with a scanning electron microscope, and then dividing the length of the long side of the rectangle by the length of the short side of the same rectangle and can be obtained using general image analysis software. The aspect ratio of the silica particles is not particularly limited and is preferably 1.0 or more.

[0028]

In a particle diameter distribution determined by a laser diffraction scattering method of the silica particles, D90/D10 which is a ratio of a particle diameter when the cumulative particle weight reaches 90% of the total particle weight from the fine particle side (D90) to a particle diameter when the cumulative particle

weight reaches 10% of the total particle weight (D10) is not particularly limited and is preferably 1.1 or more, more preferably 1.2 or more, and still more preferably 1.3 or more. Moreover, in the particle diameter
5 distribution determined by the laser diffraction scattering method in the silica particles in the polishing composition, the ratio D90/D10 of the particle diameter when the cumulative particle weight reaches 90% of the total particle weight from the fine particle side
10 (D90) to the particle diameter when the cumulative particle weight reaches 10% of the total particle weight (D10) is not particularly limited and is preferably 2.04 or less. Within such a range, defects in the surface of the polishing object can be further reduced.

15 The sizes (average primary particle diameter, average secondary particle diameter, aspect ratio, D90/D10, and the like) of the silica particles can be appropriately controlled by the selection of a method for manufacturing the silica particles or the like.

20 [0029]

 The content (concentration) of the silica particles in the polishing composition of one aspect of the present invention is preferably 0.01 mass% or more, more preferably 0.05 mass% or more, still more preferably 0.1
25 mass% or more, and particularly preferably 0.5 mass% or more. The content of the silica particles in the polishing composition is preferably 20 mass% or less, more preferably 10 mass% or less, still more preferably 5

mass% or less, and particularly preferably 3 mass% or less. When the content of the silica particles is within such a range, the occurrence of surface defects in the surface of the polishing object after polishing using the
5 polishing composition can be further suppressed. When the polishing composition contains two or more kinds of silica particles, the content of the silica particles means the total amount of the silica particles.

The polishing composition of one aspect of the
10 present invention may also contain other abrasives in addition to the silica particles. Examples of the other abrasives include metal oxide particles, such as alumina particles, zirconia particles, and titania particles, for example.

15 [0030]

<First water-soluble polymer, Second water-soluble polymer>

The polishing composition of one aspect of the present invention contains the first water-soluble
20 polymer containing the polymer compound containing a lactam ring and having a weight average molecular weight of less than 300,000 and the second water-soluble polymer containing the polymer compound containing a lactam ring and having a weight average molecular weight smaller than
25 that of the first water-soluble polymer.

The weight average molecular weight of the first water-soluble polymer is preferably 25,000 or more and less than 300,000, more preferably 30,000 or more and

200,000 or less, and still more preferably 35,000 or more and 150,000 or less.

The weight average molecular weight of the second water-soluble polymer is preferably 1,000 or more and
5 less than 25,000, more preferably 3,000 or more and 20,000 or less, and still more preferably 5,000 or more and 15,000 or less.

[0031]

As a combination of the weight average molecular
10 weight of the first water-soluble polymer and the weight average molecular weight of the second water-soluble polymer, it is preferable that the weight average molecular weight of the first water-soluble polymer is 25,000 or more and less than 300,000 and the weight
15 average molecular weight of the second water-soluble polymer is 1,000 or more and less than 25,000, it is more preferable that the weight average molecular weight of the first water-soluble polymer is 30,000 or more and 200,000 or less and the weight average molecular weight
20 of the second water-soluble polymer is 3,000 or more and 20,000 or less, and it is still more preferable that the weight average molecular weight of the first water-soluble polymer is 35,000 or more and 150,000 or less and the weight average molecular weight of the second water-soluble
25 polymer is 5,000 or more and 15,000 or less.

[0032]

Examples of the first water-soluble polymer and the second water-soluble polymer copolymer include

homopolymers containing a monomer containing a compound containing a lactam ring or copolymers containing the monomer containing a compound containing a lactam ring and a monomer containing a compound not containing a
5 lactam ring.

Examples of the monomer containing a compound containing a lactam ring include vinylpyrrolidone, vinylcaprolactam, vinylvalerolactam, vinylllauro lactam, and vinylpiperidone.

10 [0033]

Examples of the homopolymers containing the monomer containing a compound containing a lactam ring include at least one kind selected from the group consisting of polyvinylpyrrolidone, polyvinylcaprolactam,
15 polyvinylvalerolactam, polyvinylllauro lactam, and polyvinylpiperidone.

The first water-soluble polymer and the second water-soluble polymer are particularly preferably polyvinylpyrrolidones.

20 [0034]

In the polishing composition of one aspect of the present invention, the total content of the first water-soluble polymer and the second water-soluble polymer is preferably 0.05 mass% or less. Such a range is
25 advantageous for maintaining a high polishing removal rate of polysilicon.

In the polishing composition of one aspect of the present invention, a ratio of a content (W1) of the first

water-soluble polymer to a content (W2) of the second water-soluble polymer (W1/W2) is preferably 1/15 or more and 15/1 or less, more preferably 1/10 or more and 10/1 or less, and particularly preferably 1.

5 [0035]

<Basic compound>

The polishing composition of one aspect of the present invention contains a basic compound.

Examples of the basic compound contained in the
10 polishing composition of one aspect of the present invention include, for example, at least one kind of alkali compound selected from the group consisting of hydroxides of alkali metals, alkali metal salts of inorganic acids, ammonium salts of inorganic acids,
15 alkali metal salts of organic acids, ammonium salts of organic acids, and ammonia. The use of these alkali compounds enables not only the pH adjustment in an alkaline region where the silicon contained in the polishing object is easily dissolved but the realization
20 of efficient polishing without blocking the removal of silicon because most of the alkali compound is dissolved in a dispersion medium without adsorbing to the surface of the abrasives or the surface of the polishing object during polishing.

25 [0036]

Examples of the hydroxides of alkali metals include lithium hydroxides, sodium hydroxides, potassium hydroxides, and the like.

Examples of the alkali metal salts of inorganic acids include alkali metal salts of nitrous acids, such as sodium nitrite and potassium nitrite; alkali metal salts of nitric acids, such as sodium nitrate and
5 potassium nitrate; alkali metal salts of molybdic acids, such as sodium molybdate and potassium molybdate; alkali metal salts of hypochlorous acids, such as sodium hypochlorite and potassium hypochlorite; alkali metal salts of sulfuric acids, such as sodium sulfate and
10 potassium sulfate; alkali metal salts of carbonic acids, such as sodium carbonate and potassium carbonate; alkali metal salts of hydrochloric acid, such as sodium chloride and potassium chloride; alkali metal salts of phosphoric acids, such as sodium phosphate and potassium phosphate;
15 alkali metal salts of silicic acids, such as sodium silicate and potassium silicate; alkali metal salts of boric acids, such as sodium borate and potassium borate, and the like.

Examples of the ammonium salts of inorganic acids
20 include ammonium chloride, ammonium sulfate, ammonium amidosulfate, ammonium nitrate, monoammonium dihydrogen phosphate, diammonium hydrogen phosphate, triammonium phosphate, ammonium hypophosphite, ammonium carbonate, ammonium hydrogencarbonate, ammonium sulfide, ammonium
25 borate, ammonium fluoroborate, and the like.

[0037]

Examples of the alkali metal salts of organic acids include sodium acetate, potassium acetate, sodium

propionate, potassium propionate, sodium glycerate,
potassium glycerate, sodium malate, potassium malate,
sodium citrate, potassium citrate, sodium lactate,
potassium lactate, sodium tartrate, potassium tartrate,
5 sodium salicylate, potassium salicylate, sodium malonate,
potassium malonate, sodium succinate, potassium
succinate, sodium maleate, potassium maleate, sodium
phthalate, potassium phthalate, sodium oxalate, potassium
oxalate, sodium glutarate, potassium glutarate, sodium
10 abietate, potassium abietate, sodium sorbate, potassium
sorbate, sodium 2,4,6-octatriene-1-carboxylate, potassium
2,4,6-octatriene-1-carboxylate, sodium eleostearate,
potassium eleostearate, sodium 2,4,6,8-decatetraene-1-
carboxylate, potassium 2,4,6,8-decatetraene-1-
15 carboxylate, sodium retinoate, potassium retinoate, and
potassium iminodiacetate.

[0038]

Examples of the ammonium salts of organic acids
include ammonium formate, ammonium acetate, diammonium
20 oxalate, ammonium hydrogen oxalate, ammonium benzoate,
monoammonium citrate, diammonium citrate, triammonium
citrate, ammonium lactate, ammonium phthalate, ammonium
succinate, monoammonium tartrate, diammonium tartrate,
ammonium aspartate, and the like.

25 Among these alkali compounds, it is preferable to
use at least one kind selected from potassium hydroxides,
potassium salts of inorganic acids, ammonium salts of
inorganic acids, potassium salts of organic acids,

ammonium salts of organic acids, and ammonia from the purpose of preventing malfunctions of a semiconductor obtained by being polished.

[0039]

5 <Water>

The polishing composition of one aspect of the present invention contains water as a dispersion medium.

From the viewpoint of suppressing the contamination of the polishing object or the blocking of actions of
10 other components, water not containing impurities as much as possible is preferably contained as the dispersion medium. Such water is preferably water having a total content of transition metal ions of 100 ppb or less. Herein, the purity of water can be increased by an
15 operation, such as the removal of impurity ions using an ion-exchange resin, the removal of contaminants with a filter, or distillation, for example. Specifically, deionized water (ion exchange water), pure water, ultrapure water, distilled water, and the like are
20 preferably used as the water.

In usual, the water preferably accounts for 90 volume% or more of the dispersion medium contained in the polishing composition, the water more preferably accounts for 95 volume% or more thereof, the water still more
25 preferably accounts for 99 volume% or more thereof, and the water particularly preferably accounts for 100 volume% thereof.

[0040]

<Erosion inhibitor>

The polishing composition of one aspect of the present invention preferably further contains an erosion inhibitor containing a surfactant or a compound having a
5 guanidino group.

As the erosion inhibitor containing a surfactant, any one of anionic surfactants, cationic surfactants, nonionic surfactants, and amphoteric surfactants may be used and anionic surfactants are preferably used.

10 [0041]

Examples of the erosion inhibitor containing anionic surfactants include alkyl sulfuric acid (salt), alkyl phosphoric acid (salt), alkyl naphthalene sulfonic acid (salt), alkyl benzenesulfonic acid (salt),
15 polyoxyalkylene alkyl sulfuric acid (salt), polyoxyalkylene styrenated phenyl sulfuric acid (salt), polyoxyalkylene alkyl sulfosuccinic acid (salt), polyoxyalkylene allyl phenyl ether phosphoric acid (salt), polyoxyalkylene alkyl phosphoric acid (salt),
20 polyoxyalkylene alkyl acetic acid (salt), polyoxyalkylene alkyl sulfosuccinic acid (salt), alkyl sulfosuccinic acid (salt), alkyl naphthalene sulfonic acid (salt), alkyl diphenyl ether disulfonic acid (salt), and the like.
Among the above, it is preferable to use branched sodium
25 alkylbenzene sulfonate (C9-17), sodium dodecylbenzene sulfonate, or polyoxyethylene (n = 45-55) allyl phenyl ether phosphate amine salt.

[0042]

Examples of the erosion inhibitor containing the compound having a guanidino group include creatinine, arginine, and glycoamine. Among the above, creatinine or arginine is preferably used.

5 When the polishing composition of one aspect of the present invention contains the erosion inhibitor containing the surfactant, the content of the erosion inhibitor is preferably 0.00001 mass% or more, more preferably 0.00005 mass% or more, and still more
10 preferably 0.0001 mass% or more. When the polishing composition contains the erosion inhibitor containing the surfactant, the content of the erosion inhibitor is preferably 0.01 mass% or less, more preferably 0.005 mass% or less, and still more preferably 0.001 mass% or
15 less. When the content is less than 0.00001 mass%, an erosion inhibiting action is not substantially obtained. When the content exceeds 0.01 mass%, the polishing removal rate of the polysilicon film decreases.

[0043]

20 When the polishing composition of one aspect of the present invention contains the erosion inhibitor containing the compound having a guanidino group, the content of the erosion inhibitor is preferably 0.001 mass% or more, more preferably 0.01 mass% or more, and
25 still more preferably 0.05 mass% or more. When the polishing composition contains the erosion inhibitor containing the compound having a guanidino group, the content of the erosion inhibitor is preferably 5 mass% or

less, more preferably 2 mass% or less, and still more preferably 1 mass% or less. When the content is less than 0.001 mass%, the erosion inhibiting action is not substantially obtained. When the content exceeds 5
5 mass%, the polishing removal rate of the polysilicon film decreases.

[0044]

<Other additives>

The polishing composition of one aspect of the
10 present invention is preferably free of an oxidant.

The polishing composition of one aspect of the present invention may further contain known additives, such as a chelating agent, a thickener, a dispersant, a surface protective agent, a wetting agent, a surfactant
15 (surfactants different from those contained as the erosion inhibitor), and a dissolution assistant in a range where the effects of the present invention are not impaired. The content of the additives above may be set as appropriate according to the purpose of addition
20 thereof.

[0045]

<pH of polishing composition>

The pH of the polishing composition of one aspect of the present invention is preferably 8 or more. When the
25 pH is 8 or more, the polishing removal rate is further improved than that in a case where the pH is less than 8. The pH is more preferably 8.5 or more, still more preferably 9.0 or more, and particularly preferably 9.5

or more. On the other hand, from the viewpoint of safety, the pH of the polishing composition is preferably 13.0 or less, more preferably 12.0 or less, and still more preferably 11.5 or less.

5 More specifically, the pH range of the polishing composition of one aspect of the present invention is preferably 8.0 or more and 13.0 or less, more preferably 8.5 or more and 12.0 or less, still more preferably 9.0 or more and 11.5 or less, and particularly preferably 9.5
10 or more and 11.5 or less. Hence, the compounding amount of the basic compound is preferably adjusted so that the pH is within the range above.

[0046]

<Method for manufacturing polishing composition>

15 A method for manufacturing the polishing composition of one aspect of the present invention is not particularly limited. The polishing composition can be obtained by stirring and mixing the silica particles, the first water-soluble polymer, the second water-soluble
20 polymer, the basic compound, and, as necessary, other additives in the water as a dispersion medium, for example. The details of the components are as described above.

 The temperature in mixing the components is not
25 particularly limited and is preferably 10°C or more and 40°C or less. Heating may be performed in order to increase the dissolution rate. Mixing time is also not

particularly limited insofar as uniform mixing can be performed.

[0047]

<Polishing method>

5 A polishing method including polishing the polishing object containing the film containing the silicon material having a silicon-silicon bond using the polishing composition of one aspect of the present invention is described below.

10 As a polishing apparatus, a general polishing apparatus is usable which includes a polishing platen to which a holder holding a substrate having a polishing object and the like and a motor capable of varying the number of rotations and the like are attached and a
15 polishing pad (polishing cloth) can be stuck.

 As the polishing pad, general non-woven fabric, polyurethane, porous fluororesin, and the like can be used without particular limitation. The polishing pad is preferably subjected to grooving such that a polishing
20 liquid is collected.

[0048]

 With respect to the polishing conditions, the rotational speed of the polishing platen is preferably about 10 rpm (0.17 s^{-1}) or more and 500 rpm (8.3 s^{-1}) or
25 less, for example. A pressure (polishing pressure) applied to the substrate having a polishing object is preferably 0.5 psi (3.4 kPa) or more and 10 psi (68.9 kPa) or less. A method for supplying the polishing

composition to the polishing pad is also not particularly limited and a method including continuously supplying the polishing composition with a pump or the like is adopted. Although the supply amount is not limited, it is
5 preferable that the surface of the polishing pad is always covered with the polishing composition of one aspect of the present invention.

After polishing, the substrate is cleaned in running water, and then water droplets adhering onto the
10 substrate are removed with a spin dryer or the like for drying, thereby obtaining the substrate having a layer containing a metal.

[0049]

The polishing composition of one aspect of the
15 present invention may be a one-component type or may be a multi-component type including a two-component type. The polishing composition of one aspect of the present invention may be prepared by diluting a stock solution of the polishing composition 10-fold or more, for example,
20 using a diluent, such as water.

[Example 1]

[0050]

Hereinafter, Examples and Comparative Examples of the present invention are described but the present
25 invention is not limited to Examples described below. In Examples described below, technically preferable limitations are made in order to carry out the present invention but the limitations are not the indispensable

requirements of the present invention. Examples described below can be variously altered or modified and such alternations or modifications may also be included in the present invention.

5 [0051]

<Preparation of polishing composition>

(Example 1)

To water as a dispersion medium, colloidal silica having an average primary particle diameter of 90 nm was added such that the addition amount thereof was 1.5 mass% based on the total amount of a polishing composition, polyvinylpyrrolidone having a weight average molecular weight of 40,000 as the first water-soluble polymer was added such that the addition amount thereof was 0.00300 mass% based on the total amount of the polishing composition, and polyvinylpyrrolidone having a weight average molecular weight of 10,000 as the second water-soluble polymer was added such that the addition amount thereof was 0.00300 mass% based on the total amount of the polishing composition to give a mixed solution.

Thereafter, ammonia was added to the obtained mixed liquid such that the pH was 10.4, followed by stirring and mixing at room temperature (25°C) for 30 minutes, thereby preparing the polishing composition. In the polishing composition, the ratio of the content (W1) of the first water-soluble polymer to the content (W2) of the second water-soluble polymer (W1/W2) is 1.

The pH of the polishing composition (liquid temperature: 25°C) was confirmed with a pH meter (Model Number: LAQUA, manufactured by HORIBA, LTD.).

[0052]

5 (Example 2)

The addition amount of each of the polyvinylpyrrolidone having a weight average molecular weight of 40,000 and the polyvinylpyrrolidone having a weight average molecular weight of 10,000 based on the
10 total amount of a polishing composition was set to 0.00200 mass%. The polishing composition was prepared in the same manner as in Example 1 except the above.

[0053]

(Example 3)

15 Colloidal silica having an average primary particle diameter of 70 nm was used in place of the colloidal silica having an average primary particle diameter of 90 nm. The addition amount of each of the polyvinylpyrrolidone having a weight average molecular
20 weight of 40,000 and the polyvinylpyrrolidone having a weight average molecular weight of 10,000 based on the total amount of a polishing composition was set to 0.00025 mass%. Potassium hydroxide, in place of ammonia, was added such that the pH was 10.7. The polishing
25 composition was prepared in the same manner as in Example 1 except these points.

[0054]

(Example 4)

Polyvinylpyrrolidone having a weight average molecular weight of 100,000 was used in place of the polyvinylpyrrolidone having a weight average molecular weight of 40,000. A polishing composition was prepared
5 in the same manner as in Example 1 except the above.

[0055]

(Example 5)

Colloidal silica having an average primary particle diameter of 70 nm was used in place of the colloidal
10 silica having an average primary particle diameter of 90 nm. The addition amount of the polyvinylpyrrolidone having a weight average molecular weight of 40,000 based on the total amount of a polishing composition was set to 0.00050 mass%. The addition amount of the
15 polyvinylpyrrolidone having a weight average molecular weight of 10,000 based on the total amount of the polishing composition was set to 0.00005 mass%. The ratio (W1/W2) is 10. The polishing composition was prepared in the same manner as in Example 1 except these
20 points.

[0056]

(Example 6)

Colloidal silica having an average primary particle diameter of 70 nm was used in place of the colloidal
25 silica having an average primary particle diameter of 90 nm. The addition amount of the polyvinylpyrrolidone having a weight average molecular weight of 40,000 based on the total amount of a polishing composition was set to

0.00005 mass%. The addition amount of the polyvinylpyrrolidone having a weight average molecular weight of 10,000 based on the total amount of the polishing composition was set to 0.00050 mass%. The ratio (W1/W2) is 1/10. The polishing composition was prepared in the same manner as in Example 1 except these points.

[0057]

(Example 7)

Colloidal silica having an average primary particle diameter of 70 nm was used in place of the colloidal silica having an average primary particle diameter of 90 nm. The addition amount of the polyvinylpyrrolidone having a weight average molecular weight of 40,000 based on the total amount of a polishing composition was set to 0.00005 mass%. The addition amount of the polyvinylpyrrolidone having a weight average molecular weight of 10,000 based on the total amount of the polishing composition was set to 0.00005 mass%. The ratio (W1/W2) is 1. Further, ammonia was added in an amount such that the amount based on the total amount of the polishing composition was 0.194 mass%. The obtained polishing composition was confirmed to be 10.3. The polishing composition was prepared in the same manner as in Example 1 except these points.

[0058]

(Example 8)

Potassium hydroxide was added in place of ammonia. The polishing composition was prepared in the same manner as in Example 7 except these points. The pH of the obtained polishing composition was confirmed to be 10.7.

5 [0059]

(Example 9)

To water as a dispersion medium, colloidal silica having an average primary particle diameter of 70 nm was added such that the addition amount thereof was 1.5 mass% based on the total amount of a polishing composition, polyvinylpyrrolidone having a weight average molecular weight of 40,000 as the first water-soluble polymer was added such that the addition amount thereof was 0.00005 mass% based on the total amount of the polishing composition, and polyvinylpyrrolidone having a weight average molecular weight of 10,000 as the second water-soluble polymer was added such that the addition amount thereof was 0.00005 mass% based on the total amount of the polishing composition, and branched sodium alkylbenzene sulfonate (C9-17) as the erosion inhibitor was added such that the addition amount thereof was 0.0005 mass% based on the total amount of the polishing composition to give a mixed liquid.

Thereafter, potassium hydroxide was added to the obtained mixed liquid in an amount such that the addition amount thereof was 0.194 mass% based on the total amount of the polishing composition, followed by stirring and mixing at room temperature (25°C) for 30 minutes, thereby

preparing the polishing composition. The pH of the
obtained polishing composition was confirmed to be 10.7.
In the polishing composition, the ratio of the content
(W1) of the first water-soluble polymer to the content
5 (W2) of the second water-soluble polymer (W1/W2) is 1.
[0060]

(Example 10)

Sodium dodecylbenzenesulfonate was used as the
erosion inhibitor. A polishing composition was prepared
10 in the same manner as in Example 9 except the above
point. The pH of the obtained polishing composition was
confirmed to be 10.7.

(Example 11)

Polyoxyethylene (n = 45-55) allyl phenyl ether
15 phosphate amine salt was used as the erosion inhibitor.
A polishing composition was prepared in the same manner
as in Example 9 except the above point. The pH of the
obtained polishing composition was confirmed to be 10.7.
[0061]

20 (Example 12)

Polyoxyethylene (n = 8) styrenated phenyl ether
ammonium sulfate was used as the erosion inhibitor. A
polishing composition was prepared in the same manner as
in Example 9 except the above point. The pH of the
25 obtained polishing composition was confirmed to be 10.7.

(Example 13)

As the erosion inhibitor, creatinine was added such
that the addition amount thereof was 0.1 mass% based on

the total amount of a polishing composition. The polishing composition was prepared in the same manner as in Example 9 except the above point. The pH of the obtained polishing composition was confirmed to be 10.7.

5 (Example 14)

As the erosion inhibitor, arginine was added such that the addition amount was 0.1 mass% based on the total amount of a polishing composition. The polishing composition was prepared in the same manner as in Example 10 9 except the above point. The pH of the obtained polishing composition was confirmed to be 10.8.

[0062]

(Comparative Example 1)

Neither of the polyvinylpyrrolidones were added. 15 Potassium hydroxide, in place of ammonia, was added such that the pH was 10.7. A polishing composition was prepared in the same manner as in Example 1 except these points.

(Comparative Example 2)

20 Neither of the polyvinylpyrrolidones were added. A polishing composition was prepared in the same manner as in Example 1 except the above.

[0063]

(Comparative Example 3)

25 The addition amount of the polyvinylpyrrolidone having a weight average molecular weight of 40,000 based on the total amount of a polishing composition was set to 0.01000 mass%. The polyvinylpyrrolidone having a weight

average molecular weight of 10,000 was not added. The polishing composition was prepared in the same manner as in Example 1 except these points.

(Comparative Example 4)

5 The addition amount of the polyvinylpyrrolidone having a weight average molecular weight of 10,000 based on the total amount of a polishing composition was set to 0.00250 mass%. The polyvinylpyrrolidone having a weight average molecular weight of 40,000 was not added. The
10 polishing composition was prepared in the same manner as in Example 1 except these points.

[0064]

(Comparative Example 5)

 The addition amount of the polyvinylpyrrolidone
15 having a weight average molecular weight of 40,000 based on the total amount of a polishing composition was set to 0.00250 mass%. The polyvinylpyrrolidone having a weight average molecular weight of 10,000 was not added. The
 polishing composition was prepared in the same manner as
20 in Example 1 except these points.

(Comparative Example 6)

 Polyvinylpyrrolidone having a weight average molecular weight of 300,000 was added in place of the polyvinylpyrrolidone having a weight average molecular
25 weight of 40,000. A polishing composition was prepared in the same manner as in Example 1 except the above.

[0065]

<Measurement of polishing removal rate>

Using the obtained polishing compositions, CMP polishing was performed to a polysilicon film which was not doped at all (hereinafter, referred to as "Non-Doped poly-Si film"), a film containing a pattern containing a polysilicon film doped with phosphorus (hereinafter referred to as "Doped poly-PTW film"), a silicon oxide film, and a silicon nitride film to investigate the polishing removal rate.

[0066]

10 (Wafer for polishing removal rate measurement)

The measurement of the polishing removal rate of each film was performed using a CMP evaluation wafer described below.

For polishing Non-Doped poly-Si film: Blanket wafer
15 (300 mm) having a 5,000 Å thick polysilicon film formed on the surface of a silicon wafer, manufactured by Advanced Materials Technology.

For polishing Doped poly-PTW film: Wafer (300 mm) having 854 mask patterns, in which a 1000 Å thick silicon
20 nitride film was formed on a silicon wafer, a 800 Å deep trench was formed and a 2000 Å Poly-Si film doped with phosphorus (phosphorus concentration of 0.1 mass%) was formed to bury irregularities, manufactured by ADVANTEC CO., LTD.

25 [0067]

For polishing silicon oxide film: Blanket wafer (300 mm) having a 10,000 Å thick silicon oxide film (TEOS

film) formed on the surface of a silicon wafer,
manufactured by ADVANTEC CO., LTD.

For polishing silicon nitride film: Blanket wafer
(300 mm) having a 3,500 Å thick silicon nitride film (SiN
5 film) formed on the surface of a silicon wafer,
manufactured by Advanced Materials Technology.

[0068]

(Polishing apparatus and Polishing conditions)

A used polishing apparatus and polishing conditions
10 were as follows.

Polishing apparatus: CMP single-sided polishing
apparatus, 300 mm Reflexion LK, manufactured by Applied
Materials

Pad: Rigid polyurethane pad IC1010, manufactured by
15 Nitta Haas Incorporated

Polishing pressure: 2.2 psi

Number of rotations of polishing platen: 73 rpm

Number of rotations of carrier: 67 rpm

Supply of polishing composition: One-way

20 Supply amount of polishing composition: 200 ml/min

Polishing time: 60 seconds

A calculated value obtained by dividing a value,
which was obtained by subtracting the film thickness (Å)
of each film after polishing from the film thickness (Å)
25 of each film before polishing, by the polishing time
(min) was set as the polishing removal rate (Removal
Rate; RR).

The film thicknesses ($\text{\AA}$) of each film before and after the polishing were determined by an optical interference film thickness meter (Model Number: ASET-f5x, manufactured by KLA-Tencor).

5 [0069]

<Polishing test>

A polishing test was performed which includes polishing a polishing object in which a pattern containing a silicon nitride film was formed on a silicon
10 wafer through an oxide film and a polysilicon film was formed on the pattern using the obtained polishing compositions by the CMP method to form circuit patterns containing the polysilicon film.

As illustrated in FIG. 1, a polishing object 1 is
15 configured so that a pattern 3 containing a silicon nitride film is formed on a silicon wafer 1 through an oxide film 2 and a polysilicon film 4 is formed on the pattern 3. A thickness T1 of the pattern 3 containing the silicon nitride film is 1000 $\text{\AA}$. A line width H1 is
20 10 μm or 0.25 μm . An interval H2 is 10 μm or 0.25 μm . A thickness T2 of the polysilicon film 4 is 2000 $\text{\AA}$.

When ideal polishing was performed to the polishing object 10, a state was reached in which the polysilicon film 4 did not remain on the pattern 3 containing the
25 silicon nitride film, so that the entire upper surface of the pattern 3 was exposed, and then a state was reached in which circuit patterns 41 containing the polysilicon film were formed and linear patterns 31 containing the

silicon nitride film were present between the adjacent circuit patterns 41. FIG. 2 is a plan view illustrating this state.

[0070]

5 (Polishing apparatus and Polishing conditions)

A used polishing apparatus and polishing conditions were as follows.

Polishing apparatus: CMP single-sided polishing apparatus, 300 mm Reflexion LK, manufactured by Applied

10 Materials

Pad: Rigid polyurethane pad IC1010, manufactured by Nitta Haas Incorporated

Polishing pressure: 2.2 psi

Number of rotations of polishing platen: 73 rpm

15 Number of rotations of carrier: 67 rpm

Supply of polishing composition: One-way

Supply amount of polishing composition: 200 ml/min

Polishing time: 15 seconds

[0071]

20 (Performance evaluation)

The surface state of the polishing object 10 after the polishing test was observed with an atomic force microscope (Trade Name WA-1300, manufactured by Hitachi Construction Machinery Finetec Co., Ltd.) to investigate
25 the remaining state of the polysilicon film 4 to be scraped off and measure the dishing amounts of the circuit patterns 41 with a width of 10 μm and the erosion amount of the linear patterns 31 with a width of 0.25 μm .

The remaining state of the polysilicon film 4 to be scraped off was evaluated as follows.

Excellent: State in which the polysilicon film 4 did not remain on the polishing object 10 (for example, state
5 of FIG. 2).

Good: State in which the polysilicon film 4 partially remained on the polishing object 10 but no problems occurred (for example, state of FIG. 3).

Poor: State in which most of the polysilicon film 4
10 remained on the polishing object 10 and a problem occurred (for example, state of FIG. 4).

The measured values of the polishing removal rate and the polishing test results obtained above are illustrated together with the configuration of each
15 polishing composition in Table 1.

[0072]

[Table 1]

	Configuration of polishing composition (Different configuration)									
	Average primary particle diameter of abrasives (colloidal silica)	Polyvinylpyrrolidone (high molecular weight)		Polyvinylpyrrolidone (low molecular weight)		Total content of polyvinylpyrrolidones (mass%)	Erosion inhibitor		Basic compound	pH
		Mw	Ratio of Content (mass%)	Mw	Ratio of Content (mass%)		Compound name	Ratio of Content (mass%)		
Ex. 1	90 nm	40,000	0.00300	10,000	0.00300	0.00600	-	-	Ammonia	10.4
Ex. 2	90 nm	40,000	0.00200	10,000	0.00200	0.00400	-	-	Ammonia	10.4
Ex. 3	70 nm	40,000	0.00025	10,000	0.00025	0.00050	-	-	Potassium hydroxide	10.7
Ex. 4	90 nm	100,000	0.00300	10,000	0.00300	0.00600	-	-	Ammonia	10.4
Ex. 5	70 nm	40,000	0.00050	10,000	0.00005	0.00055	-	-	Ammonia	10.4
Ex. 6	70 nm	40,000	0.00005	10,000	0.00050	0.00055	-	-	Ammonia	10.4
Ex. 7	70 nm	40,000	0.00005	10,000	0.00005	0.00010	-	-	Ammonia	10.3
Ex. 8	70 nm	40,000	0.00005	10,000	0.00005	0.00010	-	-	Potassium hydroxide	10.7
Ex. 9	70 nm	40,000	0.00005	10,000	0.00005	0.00010	Branched sodium alkylbenzene sulfonate (C9-17)	0.00005	Potassium hydroxide	10.7
Ex. 10	70 nm	40,000	0.00005	10,000	0.00005	0.00010	Sodium dodecylbenzene sulfonate	0.00005	Potassium hydroxide	10.7
Ex. 11	70 nm	40,000	0.00005	10,000	0.00005	0.00010	Polyoxyethylene (n = 45-55) allyl phenyl ether phosphate amine salt	0.00005	Potassium hydroxide	10.7
Ex. 12	70 nm	40,000	0.00005	10,000	0.00005	0.00010	Polyoxyethylene (n = 8) styrenated phenyl ether ammonium sulfate	0.00005	Potassium hydroxide	10.7
Ex. 13	70 nm	40,000	0.00005	10,000	0.00005	0.00010	Creatinine	0.1	Potassium hydroxide	10.7
Ex. 14	70 nm	40,000	0.00005	10,000	0.00005	0.00010	Arginine	0.1	Potassium hydroxide	10.8
Comp. Ex. 1	90 nm	-	-	-	-	-	-	-	Potassium hydroxide	10.7
Comp. Ex. 2	90 nm	-	-	-	-	-	-	-	Ammonia	10.5
Comp. Ex. 3	90 nm	40,000	0.01000	-	-	0.01000	-	-	Ammonia	10.4
Comp. Ex. 4	90 nm	-	-	10,000	0.00250	0.00250	-	-	Ammonia	10.4
Comp. Ex. 5	90 nm	40,000	0.00250	-	-	0.00250	-	-	Ammonia	10.4
Comp. Ex. 6	90 nm	300,000	0.00300	10,000	0.00300	0.00600	-	-	Ammonia	10.4

	Polishing performance							
	Polishing removal rate (Å/min)				Poly-Si remaining reducing effect			
	Non-Doped Poly-Si	Doped poly-PTW	TEOS Si oxide film	SiN			Dishing (Å)	Erosion (Å)
Ex. 1	2903	3593	50	35		Excellent	139	64
Ex. 2	2796	3105	63	5		Excellent	143	81
Ex. 3	2378	2017	70	22		Excellent	157	87
Ex. 4	2256	3157	42	41		Excellent	135	75
Ex. 5	2373	2012	67	25		Good	157	83
Ex. 6	2416	2054	69	24		Excellent	161	88
Ex. 7	2456	2109	66	24		Good	160	87
Ex. 8	2320	2835	73	28		Excellent	146	70
Ex. 9	2480	2442	74	24		Excellent	141	58
Ex. 10	2500	2657	70	29		Excellent	139	57
Ex. 11	2448	2776	74	27		Good	139	52
Ex. 12	2439	2398	69	18		Excellent	143	57
Ex. 13	2600	2813	72	26		Excellent	149	65
Ex. 14	2217	2944	75	28		Excellent	151	66
Comp. Ex. 1	2432	2537	183	69		Excellent	173	132
Comp. Ex. 2	2646	3040	50	45		Excellent	137	133
Comp. Ex. 3	2212	3457	34	45		Poor	99	46
Comp. Ex. 4	2665	3529	76	49		Excellent	147	98
Comp. Ex. 5	2653	3454	57	46		Excellent	154	127
Comp. Ex. 6	1973	3025	48	42		Poor	87	39

[0073]

In the case of the polishing using the polishing compositions of Examples 1 to 4, 6, 8 to 10, 12 to 14, the polysilicon film 4 to be scraped off did not remain and
5 the state illustrated in FIG. 2 was reached (which is indicated as "Excellent" in Table 1). The dishing amount of the circuit patterns 41 was 161 Å or less, which is lower than 173 Å of Comparative Example 1. The erosion amount of the linear patterns 31 was 88 Å or less, which
10 is lower than 132 Å of Comparative Example 1.

[0074]

In the case of the polishing using the polishing compositions of Examples 5, 7, 11, the polysilicon film 4 to be scraped off partially remained but most of the
15 patterns 31 containing the silicon nitride film between the circuit patterns 41 were almost exposed (for example, state of FIG. 3) and no problems occurred (which is indicated as "Good" in Table 1). The dishing amount of the circuit patterns 41 was 157 Å, which is lower than 173
20 Å of Comparative Example 1. The erosion amount of the linear patterns 31 was 87 Å or less, which is lower than 132 Å of Comparative Example 1.

[0075]

In the case of the polishing using the polishing compositions of Comparative Examples 1, 2, 4, 5, the polysilicon film 4 to be scraped off did not remain and a
25 state illustrated in FIG. 2 was reached (which is indicated as "Good" in Table 1). In Comparative Example 1, the

dishing amount of the circuit patterns 41 was as high as 173 Å. The erosion amount of the linear patterns 31 was also as high as 132 Å. In Comparative Example 2, the erosion amount of the linear patterns 31 was as high as 133 Å. In Comparative Example 4, the erosion amount of the linear patterns 31 was as high as 98 Å. In Comparative Example 5, the erosion amount of the linear patterns 31 was as high as 127 Å.

[0076]

10 In the case of the polishing using the polishing compositions of Comparative Example 3 and Comparative Example 6, most of the polysilicon film 4 to be scraped off remained. For example, as illustrated in FIG. 4, there were also a large number of portions in a state in which 15 the patterns 31 containing the silicon nitride film between the circuit patterns 41 were not exposed at all in the entire longitudinal direction of the wiring lines (which is indicated as "Poor" in Table 1).

[0077]

20 The results above showed that the polishing compositions of Examples 1 to 14 obtained an effect capable of reducing the remaining of the polysilicon film to be scraped off and an inhibitory effect of the dishing and the erosion. On the other hand, the polishing compositions 25 of Comparative Examples 1 to 6 were not able to obtain either one of the effects. In the polishing compositions of Examples 1 to 14, the polishing removal rates of the polysilicon films were 2256 to 2903 Å/min, which were

almost equal to the polishing removal rates (2432 to 2646 Å/min) of the polysilicon films by the polishing compositions of Comparative Examples 1 and 2 not containing polyvinylpyrrolidone.

5 [0078]

When the polishing compositions of Example 7 and Example 8 different only in the kind of the basic compound contained therein are compared with each other, the remaining reducing effect of the polysilicon film 4 to be
10 scraped off was higher and the dishing amount of the circuit patterns 41 and the erosion amount of the linear patterns 31 were smaller in the polishing using the polishing composition of Example 8 containing potassium hydroxide than in the polishing using the polishing
15 composition of Example 7 containing ammonia. This result shows that potassium hydroxide is more preferably used as the basic compound than ammonia.

[0079]

A comparison between the polishing composition of
20 Example 8 with the polishing compositions of Examples 9 to 14 different only in whether the erosion inhibitor is contained shows that the erosion amount can be further reduced in the polishing using the polishing compositions of Examples 9 to 14 containing the erosion inhibitor than
25 in the polishing using the polishing composition of Example 8 not containing the erosion inhibitor.

EXPLANATION OF REFERENCE NUMERALS

[0080]

	10	polishing object
	1	silicon wafer
	2	oxide film
5	3	pattern containing silicon nitride film
	4	polysilicon film
	41	circuit pattern containing polysilicon film
	31	linear pattern containing silicon nitride film

WHAT IS CLAIMED IS:

1. A polishing composition comprising:

silica abrasives;

a first water-soluble polymer containing a polymer
5 compound containing a lactam ring and having a weight
average molecular weight of 25,000 or more and less than
300,000;

a second water-soluble polymer containing a polymer
compound containing a lactam ring and having a weight
10 average molecular weight smaller than the weight average
molecular weight of the first water-soluble polymer;

a basic compound; and

water,

wherein, the weight average molecular weight of the
15 second water-soluble polymer is 1,000 or more and less
than 25,000,

wherein, total content of the first water-soluble
polymer and the second water-soluble polymer is 0.006 or
less weight %, and

20 wherein, a ratio of a content (W1) of the first
water-soluble polymer to a content (W2) of the second
water soluble polymer (W1/W2) is 1/15 or more and 15/1 or
less.

25 2. The polishing composition according to Claim
1, wherein

the first water-soluble polymer and the second
water-soluble polymer are homopolymers containing a

monomer containing a compound containing a lactam ring or copolymers containing a monomer containing a compound containing a lactam ring and a monomer containing a compound not containing a lactam ring.

5

3. The polishing composition according to Claim 2 comprising:

as the monomer containing a compound containing a lactam ring, at least one kind selected from the group consisting of vinylpyrrolidone, vinylcaprolactam, vinylvalerolactam, vinylllauro lactam, and vinylpiperidone.

4. The polishing composition according to Claim 2 comprising:

as the homopolymer, at least one kind selected from the group consisting of polyvinylpyrrolidone, polyvinylcaprolactam, polyvinylvalerolactam, polyvinylllauro lactam, and polyvinylpiperidone.

5. The polishing composition according to Claim 1, wherein

the first water-soluble polymer and the second water-soluble polymer are polyvinylpyrrolidones.

6. The polishing composition according to any one of Claims 1 to 5, wherein

a total content of the first water-soluble polymer and the second water-soluble polymer is 0.05 mass% or less.

5 7. The polishing composition according to any one of Claims 1 to 6 further comprising:

an erosion inhibitor containing a surfactant or a compound having a guanidino group.

10 8. The polishing composition according to Claim 7, wherein

the erosion inhibitor contains a surfactant and the surfactant is an anionic surfactant.

15 9. The polishing composition according to Claim 7, wherein

the erosion inhibitor contains a compound having a guanidino group and the compound having a guanidino group is creatinine or arginine.

20

10. A polishing method comprising:

polishing a polishing object containing a film containing a silicon material having a silicon-silicon bond using the polishing composition according to any one
25 of Claims 1 to 9.

11. A polishing method comprising:

polishing a polishing object having a film
containing a silicon material having a silicon-silicon
bond formed on a pattern containing an insulating film
using the polishing composition according to any one of
5 Claims 1 to 9 by a CMP method to form a circuit pattern
containing the silicon material.